

CORM annual conference, NRC, Ottawa, CANADA
June 1, 2012

New automated laser facility for detector calibrations

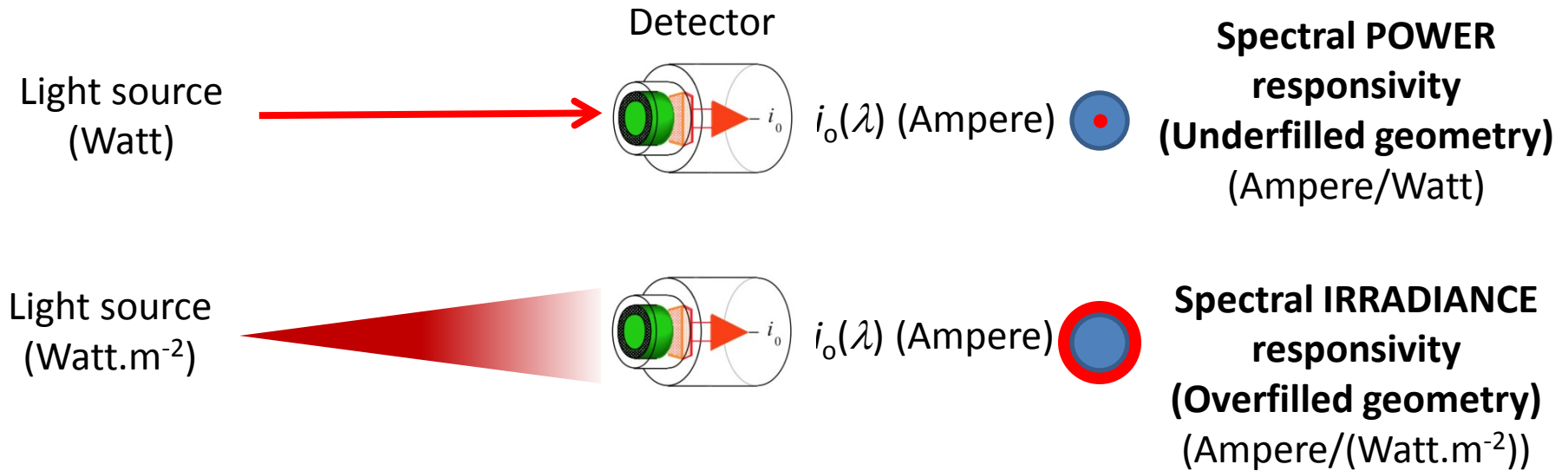
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Overview

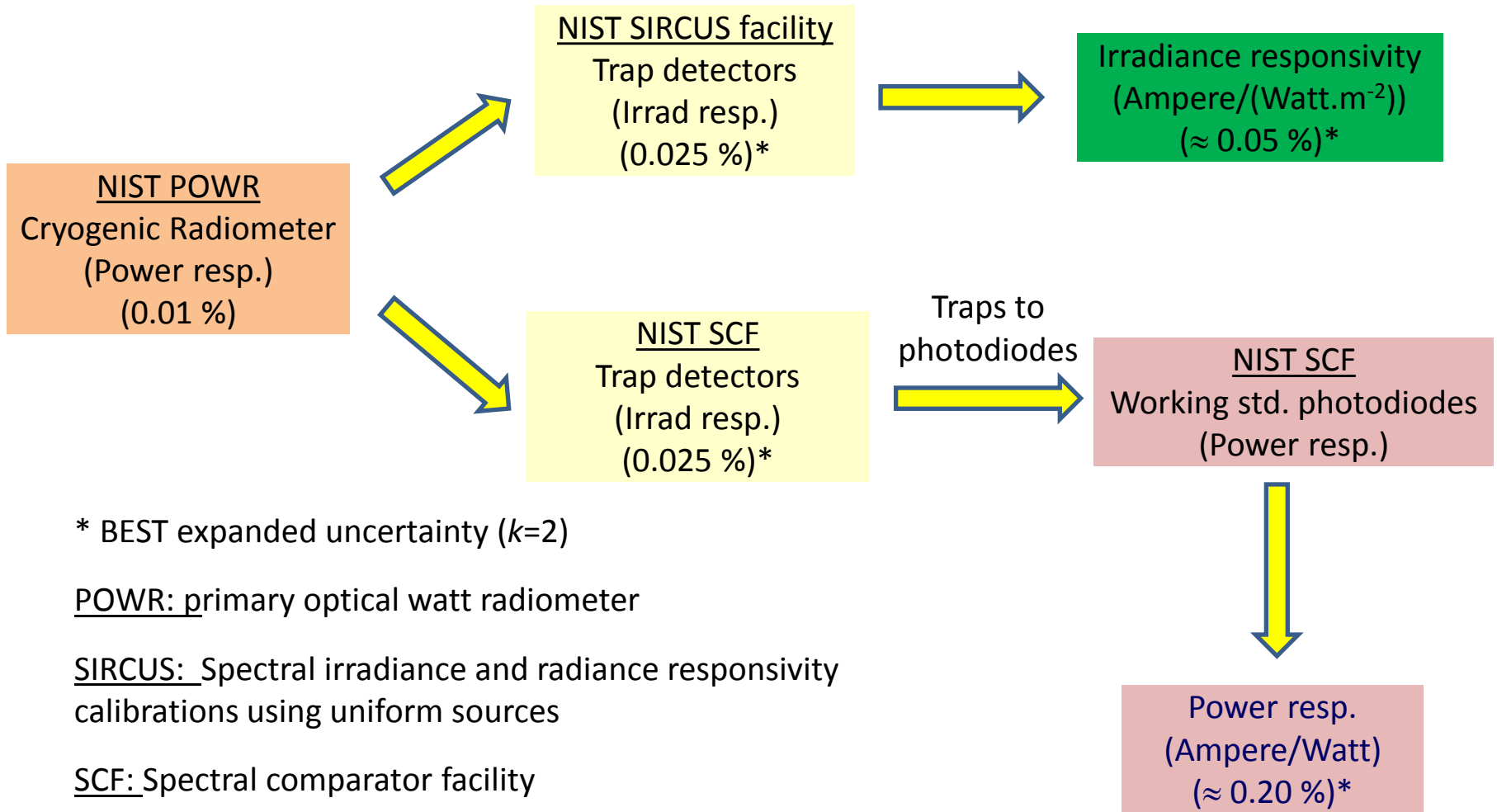
- Introduction
- Existing spectral calibration facilities
- New 1 kHz optical parametric oscillator (OPO) based calibration system
- Conclusion

Spectral calibration of optical sensors



- SI base unit -luminous intensity: candela
- SI base unit –radiance temperature: Kelvin
- Colorimetry and radiometry
- Spectral irradiance scale (FEL lamps)
- ...

Existing NIST spectral calibration facilities



* BEST expanded uncertainty ($k=2$)

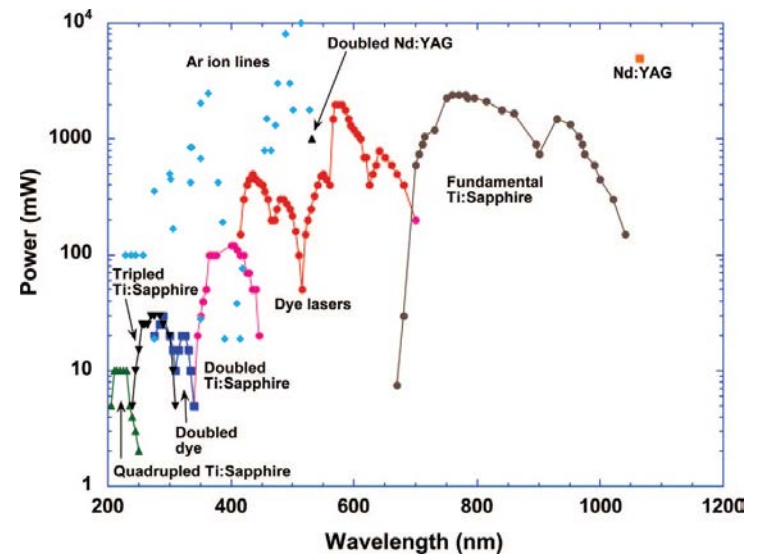
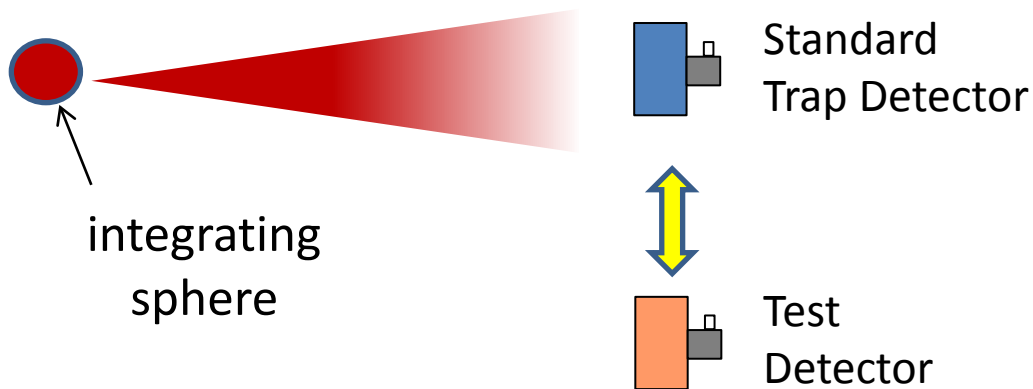
POWR: primary optical watt radiometer

SIRCUS: Spectral irradiance and radiance responsivity calibrations using uniform sources

SCF: Spectral comparator facility

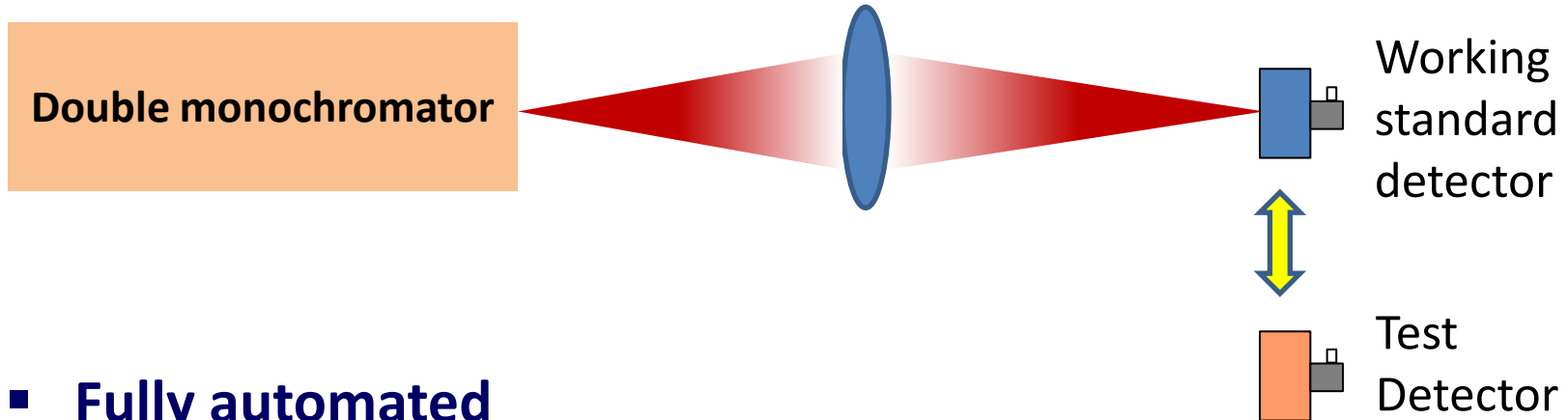
Trap detector: specially configured, multi-element silicon photodiodes detector with high performance.

The NIST SIRCUS facility



- Continuous spectral coverage from UV to NIR
- Continuous wave (CW) or quasi-CW tunable lasers based research facility
- high power (e.g., 100 mW), narrow bandwidth (<0.01 nm)
- Used for realization of SI base units: Kelvin and candela
- Provide calibrations for primary radiometric standards and for remote sensing instruments ...
- **Difficult to automate & high-cost**

NIST SCF

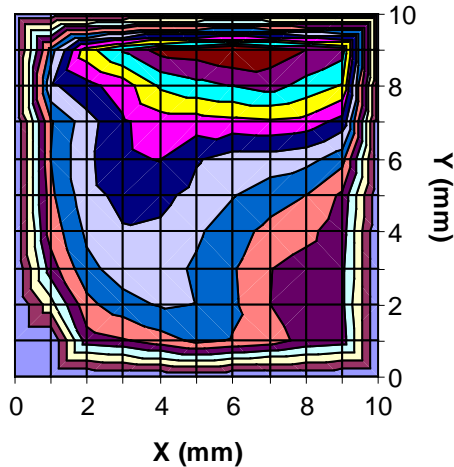


- **Fully automated**
- Lamp-monochromator based calibration facility, no fringe problem
- Major facility to disseminate NIST Scale to industry
- Low radiant power (μW level), broad bandwidth (4 nm)
- Designed for power responsivity
- Large uncertainties to acquire irradiance responsivities (mapping method does not work well!)

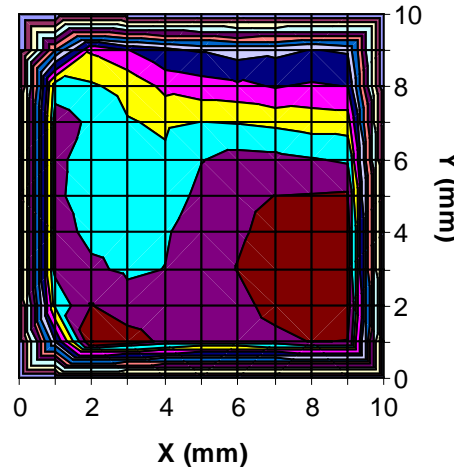
Spatial uniformity of a Si photodiode

Acknowledgement to
Ping-shine Shaw, NIST

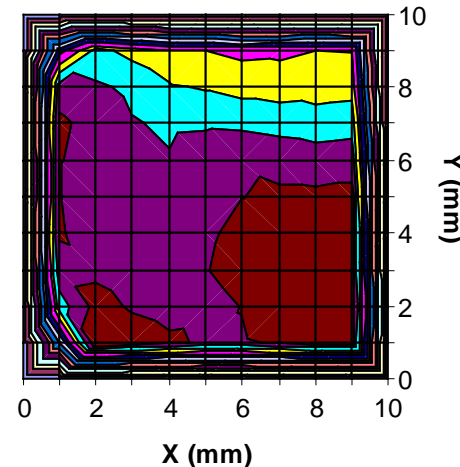
205 nm



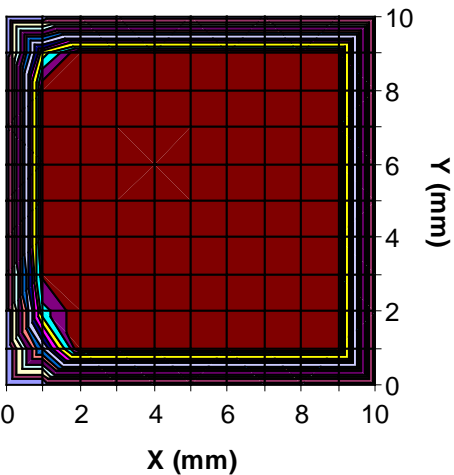
230 nm



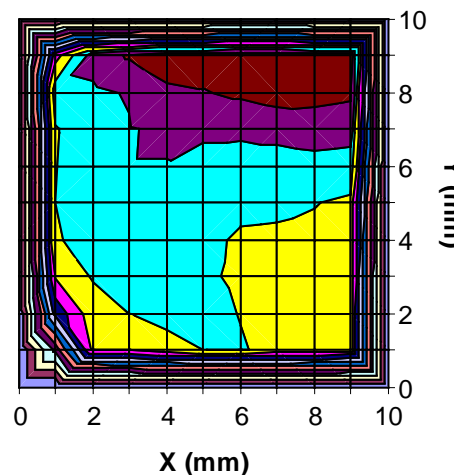
250 nm



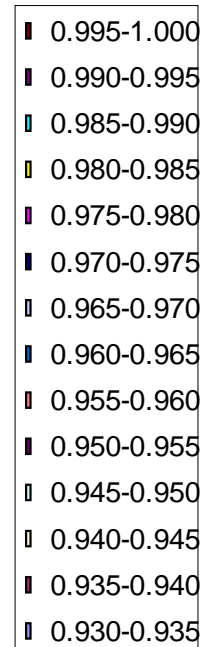
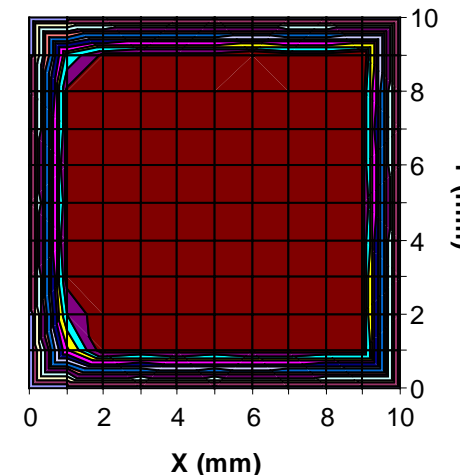
265 nm



320 nm

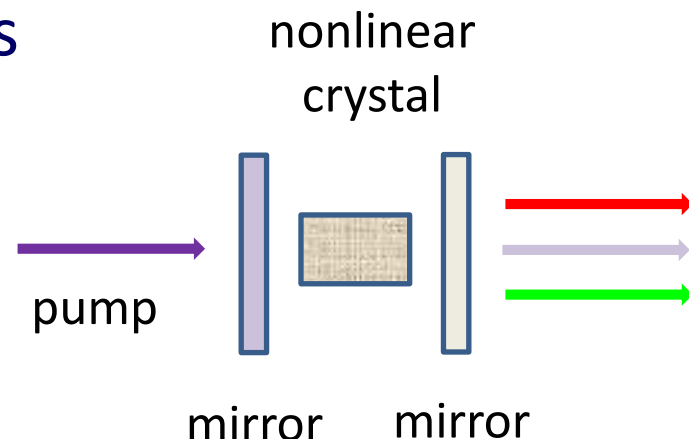


500 nm



Fully automated tunable OPO-based laser sources

- OPO: optical parametric oscillators
- Fully automated
- Large tunable range
- Portable
- Much lower cost
- Low repetition rate (10 Hz to 1000 Hz)
- Narrow pulse width, extremely low duty cycle (e.g., 10^{-6})
- Pulse to pulse variation and difficult to stabilize
- Trans-impedance amplifiers don't work well

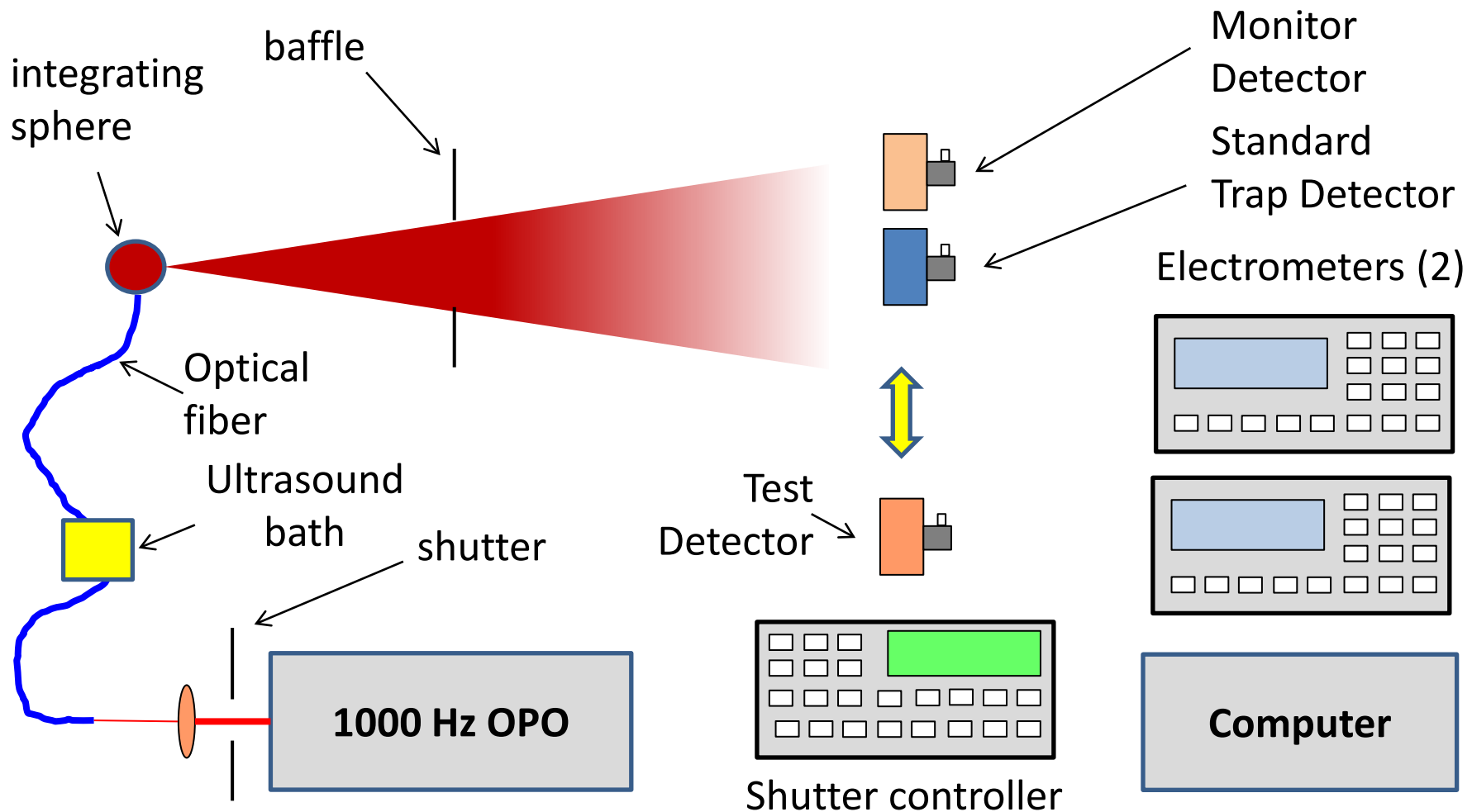


Have not been used as calibration source yet

Key questions

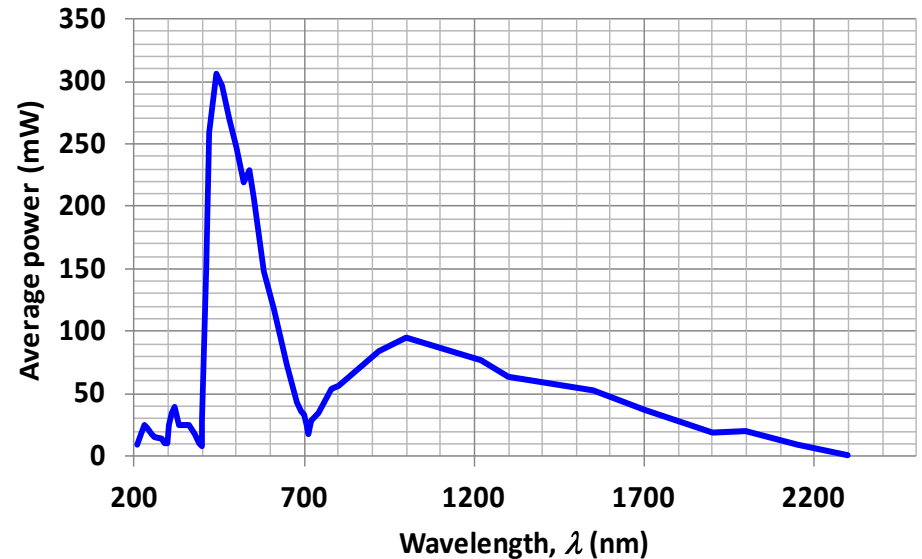
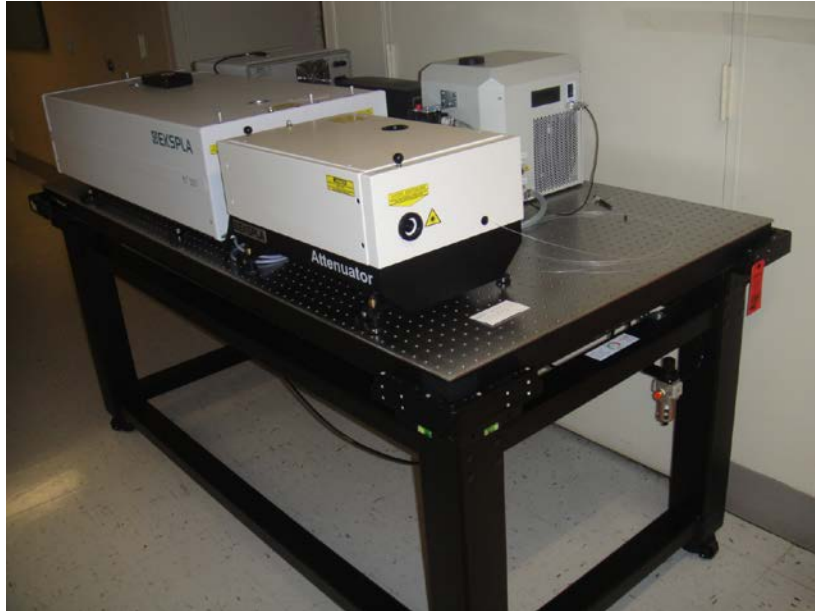
- Can pulse lasers be used for calibration of detectors with small uncertainties?
- How to overcome fluctuation of a pulsed laser and obtain repeatable results?
- Will detectors be saturated?
- Is a pulse laser equivalent to a CW laser for detector calibrations?

Schematic of the new automated calibration system



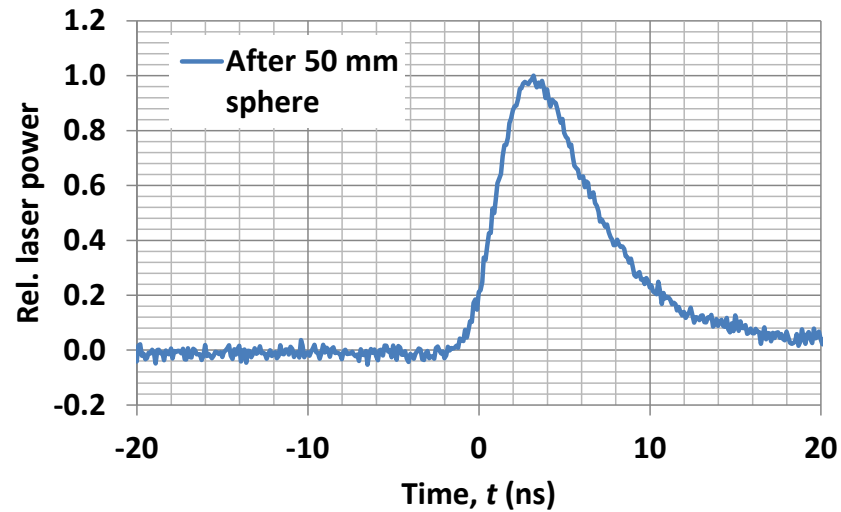
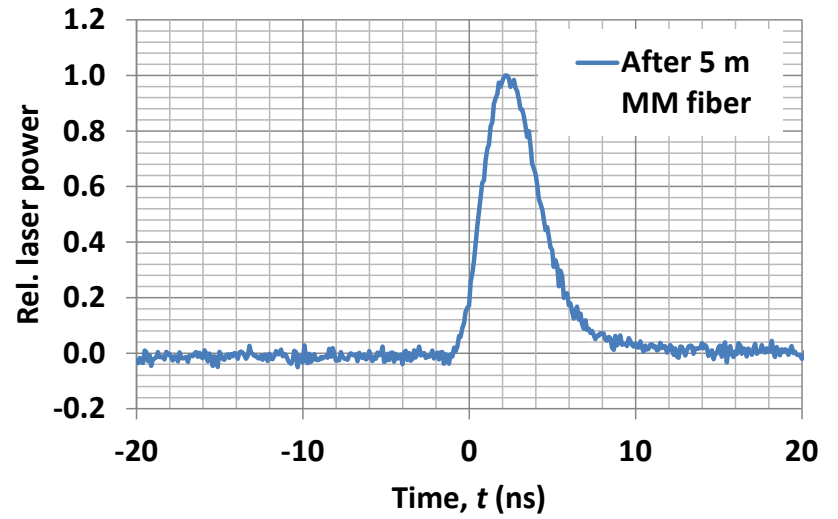
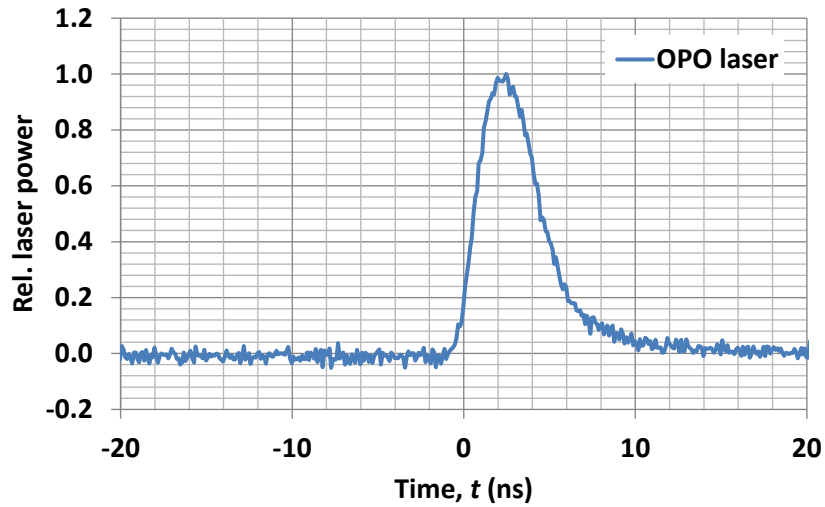
$$R_{test}(\lambda) = R_{standard}(\lambda) \times Q_{test}^M(\lambda) / Q_{standard}^M(\lambda)$$

The automated OPO system

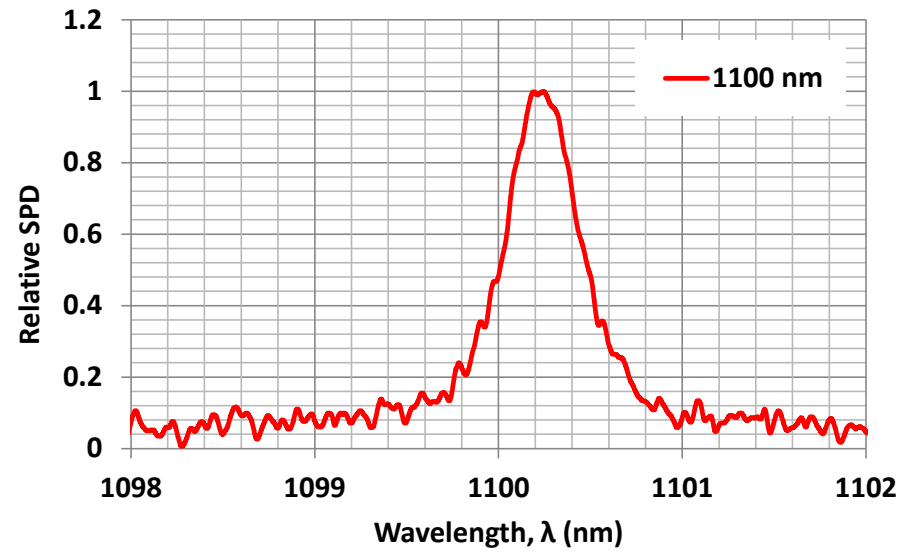
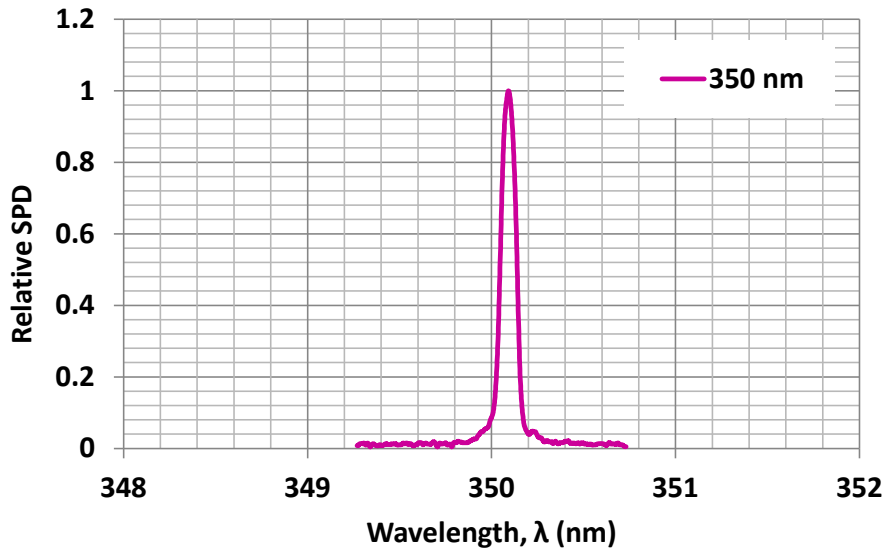
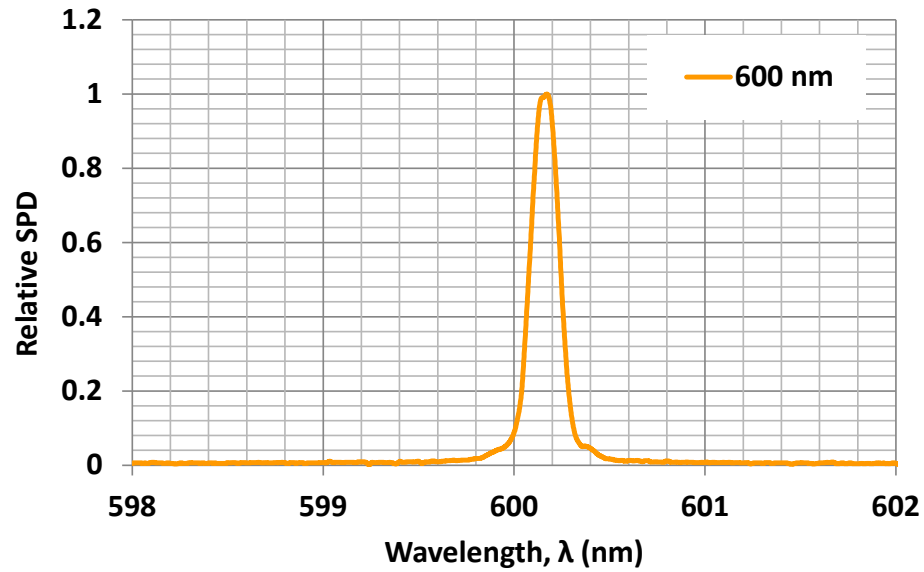


- 210 nm to 2400 nm tunable range
- 1 kHz repetition rate
- 5 ns pulse width
- 5 – 8 cm^{-1} bandwidth (≈ 0.2 nm in visible range)

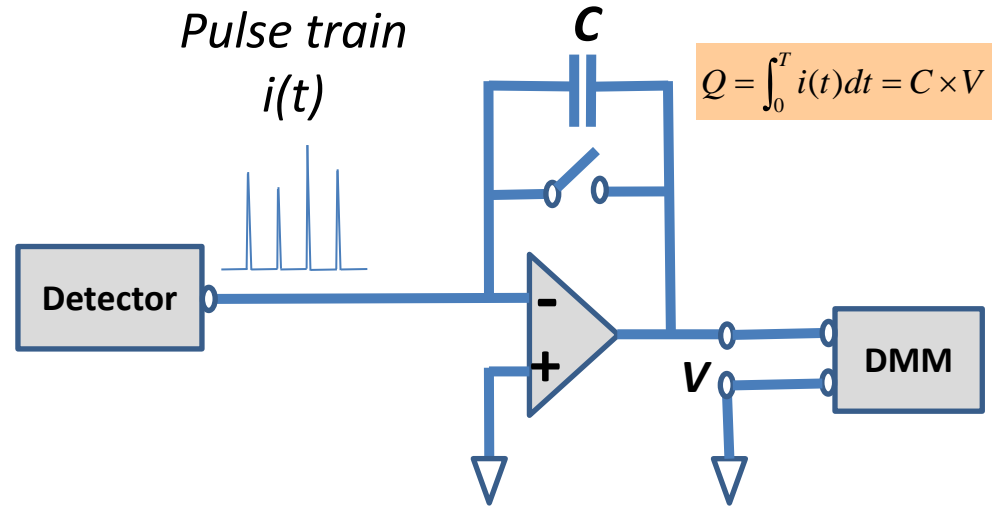
OPO Pulse waveforms



OPO spectra

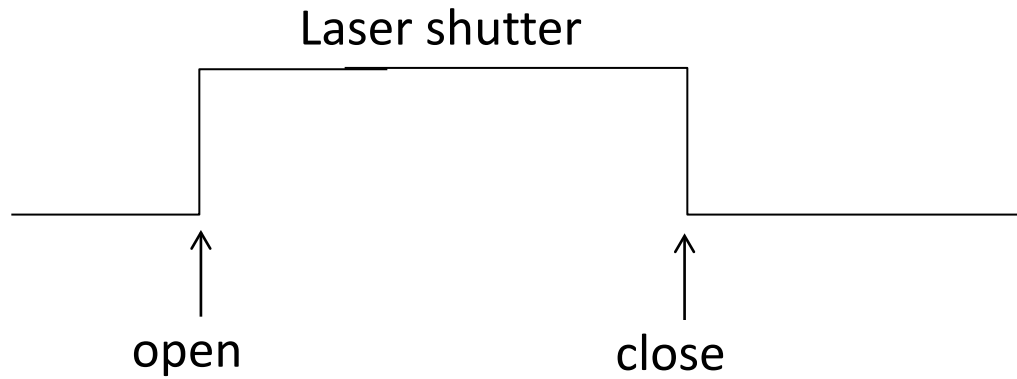
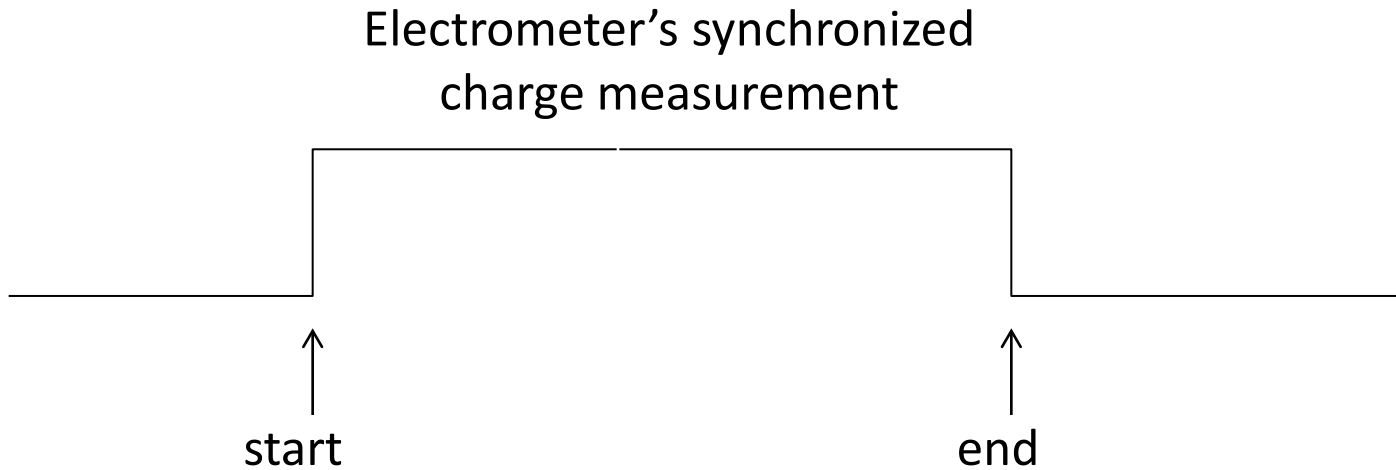


The electrometers



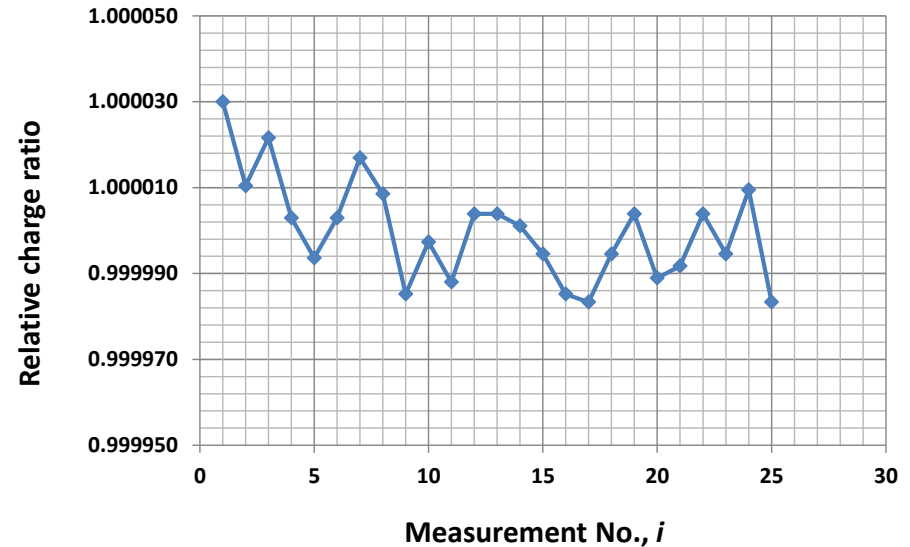
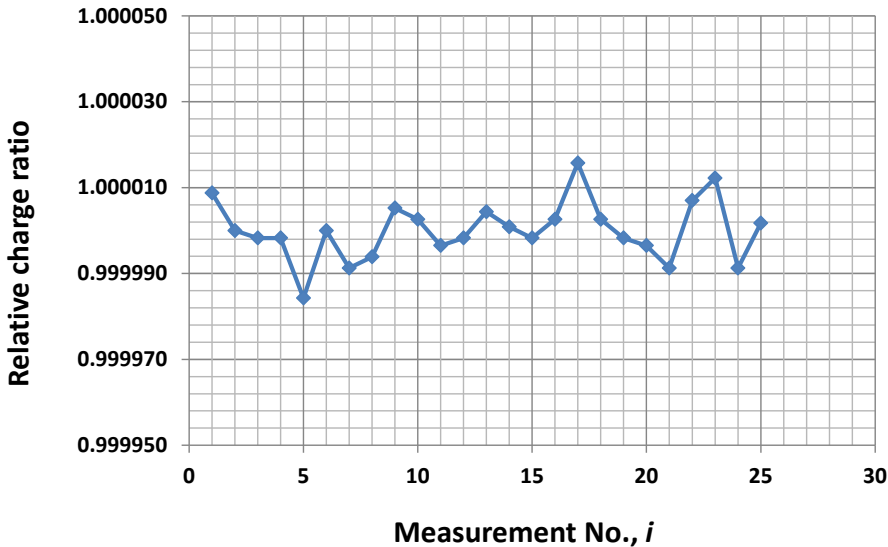
- Charge measurement function from 2 nC to 2 μ C using a charge amplifier
- < 3 fA bias current
- < 20 μ V burden voltage
- High performance multichannel switching card

Measurement Timing



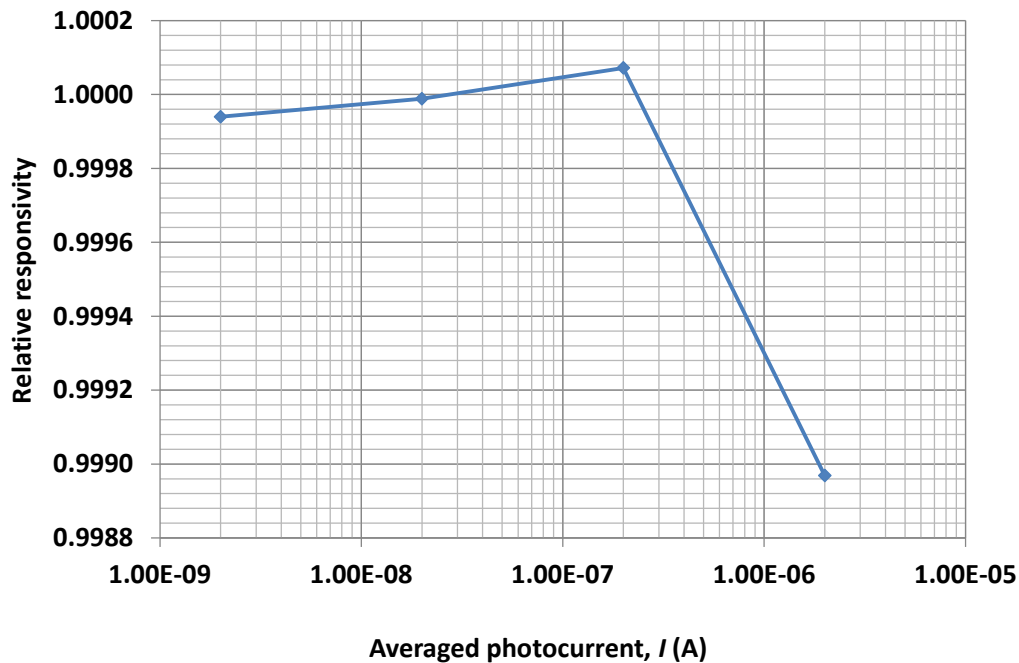
Measurement repeatability

1 s integration time for each point



- two Hamamatus S2281 silicon photodiodes (PD)
- standard deviation = **7 ppm!**
- one 3 silicon PD trap and one S2281 Si PD
- standard deviation = **12 ppm!**

Detector non-linearity test



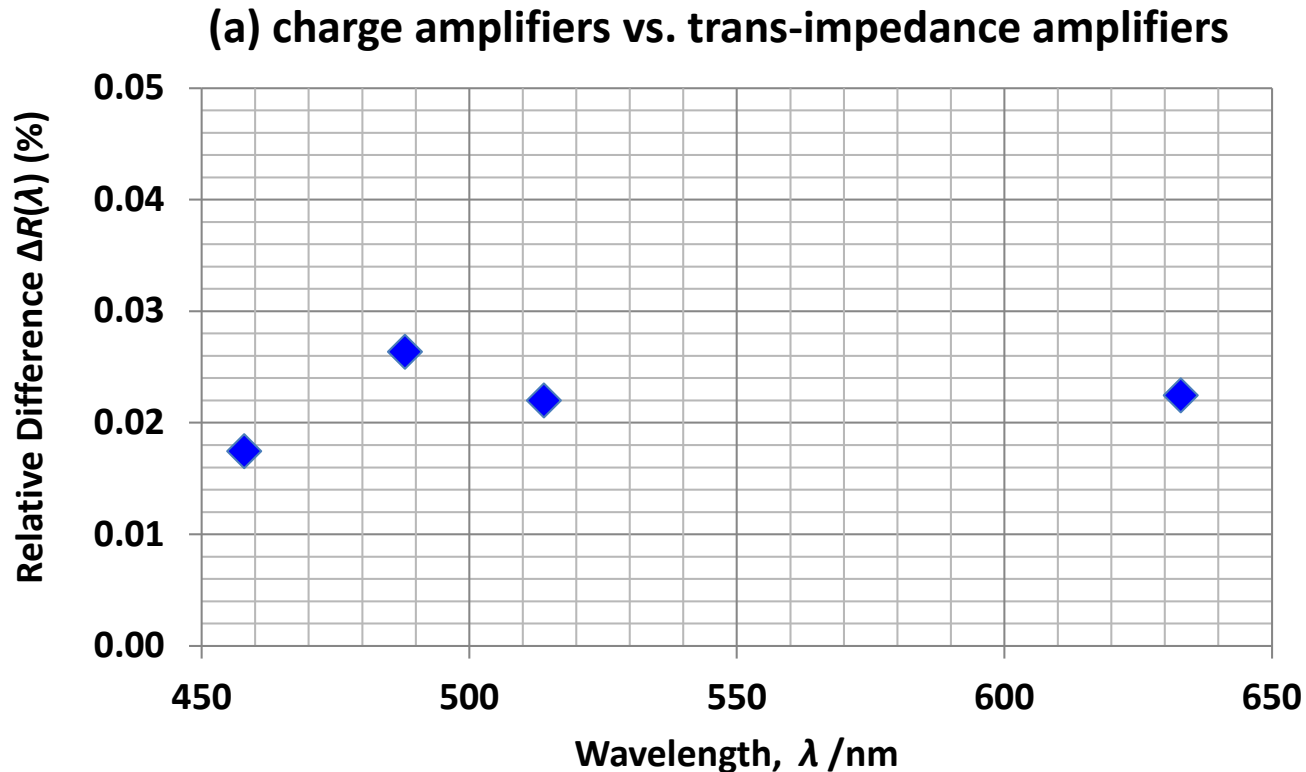
Obtained by normalizing the charge ratio $r(P_i)$ of the test detector (S2281 PD) to reference detector (S2281 PD with 2 orders of magnitude lower signal).

OPO at 450 nm.

Saturation starts at peak=100 mA, averaged=1 μ A.

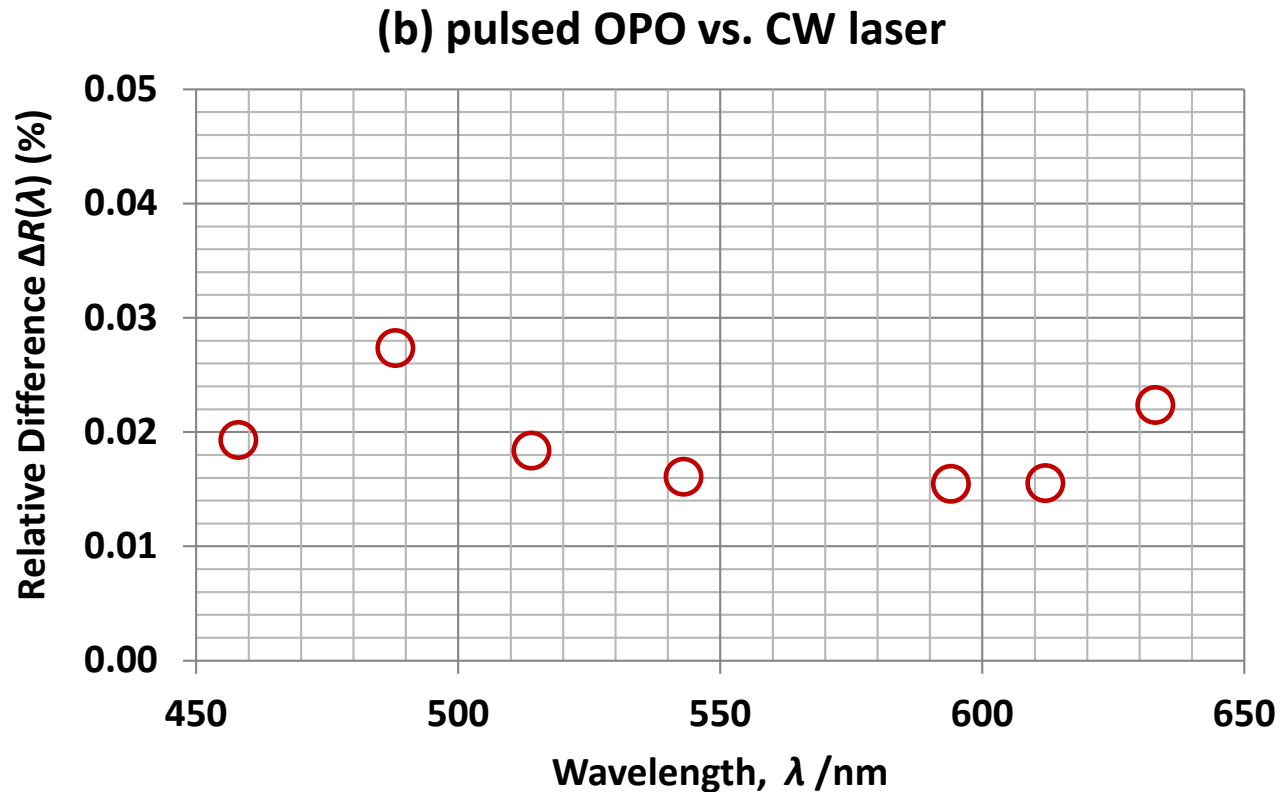
- 1) Nonlinearity depends on the detector and laser wavelength.
- 2) The instantaneous photocurrent without causing nonlinearity is several orders of magnitude higher than the threshold nonlinear DC photocurrent (0.1 – 1 mA typically).
- 3) The level of allowed averaged photocurrent is several orders of magnitude lower than the threshold nonlinear DC photocurrent.

Validation: charge amp vs trans-impedance amp



“**CW laser** + charge amplifiers” vs. “**CW laser** + trans-impedance amplifiers”
Difference in measured responsivity is ≈ 0.02 %.

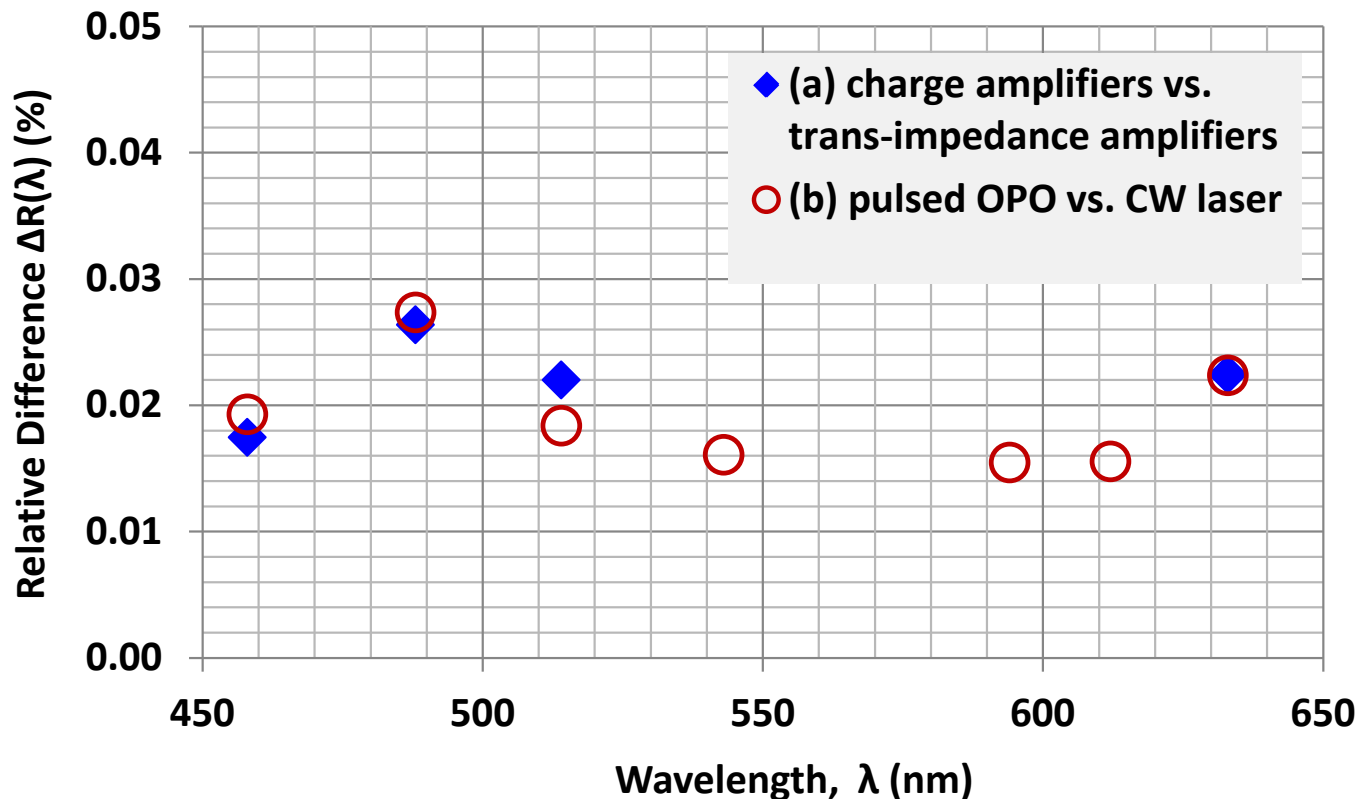
Validation: 1 kHz pulsed OPO vs CW lasers



“Pulsed OPO + charge amplifiers” vs. “CW laser + trans-impedance amplifiers”

Difference in measured responsivity is also ≈ 0.02 %

Comparison of Results



Replacing **CW laser** with **pulsed OPO** for charge amplifiers does not make difference in measured responsivity.

Pulsed OPO \longleftrightarrow **CW laser**.

Uncertainty budget

Uncertainty component	Relative standard unc. (%)	
	Type A	Type B
Reference trap detector		0.020
OPO wavelength (0.02 nm)		0.005
Sphere source irradiance non-uniformity		0.005
Detector reference plane		0.010
Detector non-linearity		0.005
Transfer to test detector	0.005	
Electrometer (range to range gain error)		0.005
Combined uncertainty (%)	0.025	
Expanded uncertainty ($k=2$) (%)	0.05	

Conclusions

- A fully automated laser facility using a kHz pulsed OPO for calibration of detectors and instruments has been developed and validated. The estimated uncertainty is 0.05 % ($k=2$).
- The new facility is to be used for calibration of photometers, colorimeters, and spectroradiometers with significantly reduced uncertainty.
- The developed method may be used in other applications:
 - transmittance and reflectance
 - surface color and appearance
 - optical medical imaging
 - ...

Acknowledgements

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and many other colleagues

THANK YOU